

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):	ZAIT, Eitan, et al.	Examiner:	FRASER, Stewart A.
Serial No.:	10/564,972	Group Art Unit:	2625
Filed:	August 1, 2006	Confirmation No.	7182
Title:	METHOD FOR CORRECTING CRITICAL DIMENSION VARIATIONS IN PHOTOMASKS		

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Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

Sir:

This Amendment is being filed in response to the final Office action dated August 11, 2009 issued by the United States Patent and Trademark Office in connection with the above-identified Application. A response to the August 11, 2009 final Office action was due November 11, 2009. Applicants are concurrently filing a Petition for a Two-Month Extension of Time, including the required fee. Therefore, a response is due January 11, 2009. Accordingly, this Amendment is being timely filed. A request for continued examination is also concurrently being filed, including the required fee.

Kindly amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page **2** of this paper.

Remarks/Arguments begin on page **5** of this paper.